

OptiMOS™ 3 M-Series Power-MOSFET
Features

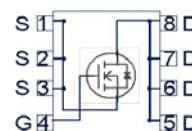
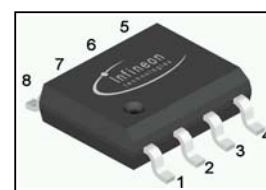
- Optimized for 5V driver application (Notebook, VGA, POL)
- Low FOM_{SW} for High Frequency SMPS
- 100% Avalanche tested
- N-channel
- Very low on-resistance $R_{DS(on)}$ @ $V_{GS}=4.5\text{ V}$
- Excellent gate charge x $R_{DS(on)}$ product (FOM)
- Qualified for consumer level application
- Pb-free plating; RoHS compliant
- Halogen-free according to IEC61249-2-21


Halogen-Free

Type	Package	Marking
BSO065N03MS G	PG-DSO-8	065N03MS

Product Summary

V_{DS}		30	V
$R_{DS(on),max}$	$V_{GS}=10\text{ V}$	6.5	mΩ
	$V_{GS}=4.5\text{ V}$	8	
I_D		16	A

PG-DSO-8

Maximum ratings, at $T_J=25\text{ °C}$, unless otherwise specified

Parameter	Symbol	Conditions	Value		Unit
			10 secs	steady state	
Continuous drain current ¹⁾	I_D	$V_{GS}=10\text{ V}, T_A=25\text{ °C}$	16	13	A
		$V_{GS}=10\text{ V}, T_A=90\text{ °C}$	10.9	8.6	
		$V_{GS}=4.5\text{ V}, T_A=25\text{ °C}$	14.2	11	
		$V_{GS}=4.5\text{ V}, T_A=90\text{ °C}$	9.8	7.8	

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	

Thermal characteristics

Thermal resistance, junction - soldering point	R_{thJS}		-	-	35	K/W
Thermal resistance, junction - ambient	R_{thJA}	minimal footprint, $t_p \leq 10$ s	-	-	110	
		minimal footprint, steady state	-	-	150	
		6 cm ² cooling area ¹⁾ , $t_p \leq 10$ s	-	-	50	
		6 cm ² cooling area ¹⁾ , steady state	-	-	80	

Electrical characteristics, at $T_j=25$ °C, unless otherwise specified

Static characteristics

Drain-source breakdown voltage	$V_{(BR)DSS}$	$V_{GS}=0$ V, $I_D=1$ mA	30	-	-	V
Gate threshold voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}$, $I_D=250$ μ A	1	-	2	
Zero gate voltage drain current	I_{DSS}	$V_{DS}=30$ V, $V_{GS}=0$ V, $T_j=25$ °C	-	0.1	10	μ A
		$V_{DS}=30$ V, $V_{GS}=0$ V, $T_j=125$ °C	-	10	100	
Gate-source leakage current	I_{GSS}	$V_{GS}=16$ V, $V_{DS}=0$ V	-	10	100	nA
Drain-source on-state resistance	$R_{DS(on)}$	$V_{GS}=4.5$ V, $I_D=14.2$ A	-	6.4	8	m Ω
		$V_{GS}=10$ V, $I_D=16$ A	-	5.4	6.5	
Gate resistance	R_G		0.6	1.3	2.3	Ω
Transconductance	g_{fs}	$ V_{DS} > 2 I_D R_{DS(on)max}$, $I_D=16$ A				

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	

Dynamic characteristics

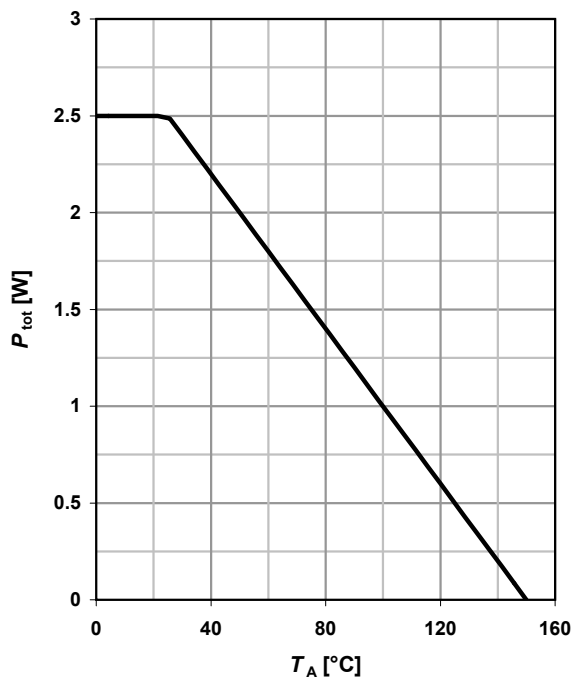
Input capacitance	C_{iss}	$V_{GS}=0\text{ V}, V_{DS}=15\text{ V},$ $f=1\text{ MHz}$	-	2300	3100	pF
Output capacitance	C_{oss}		-	710	940	
Reverse transfer capacitance	C_{rss}		-	47	-	
Turn-on delay time	$t_{d(on)}$	$V_{DD}=15\text{ V}, V_{GS}=4.5\text{ V},$ $I_D=16\text{ A}, R_G=1.6\text{ }\Omega$	-	12.2	-	ns
Rise time	t_r		-	6.2	-	
Turn-off delay time	$t_{d(off)}$		-	15.6	-	
Fall time	t_f		-	6.4	-	

Gate Charge Characteristics⁴⁾

Gate to source charge	Q_{gs}	$V_{DD}=15\text{ V}, I_D=16\text{ A},$ $V_{GS}=0\text{ to }4.5\text{ V}$	-	6.4	-	nC
Gate charge at threshold	$Q_{g(th)}$		-	3.7	-	
Gate to drain charge	Q_{gd}		-	3.2	-	
Switching charge	Q_{sw}		-	5.9	-	
Gate charge total	Q_g		-	14.4	19	
Gate plateau voltage	$V_{plateau}$		-	2.8	-	V

1 Power dissipation

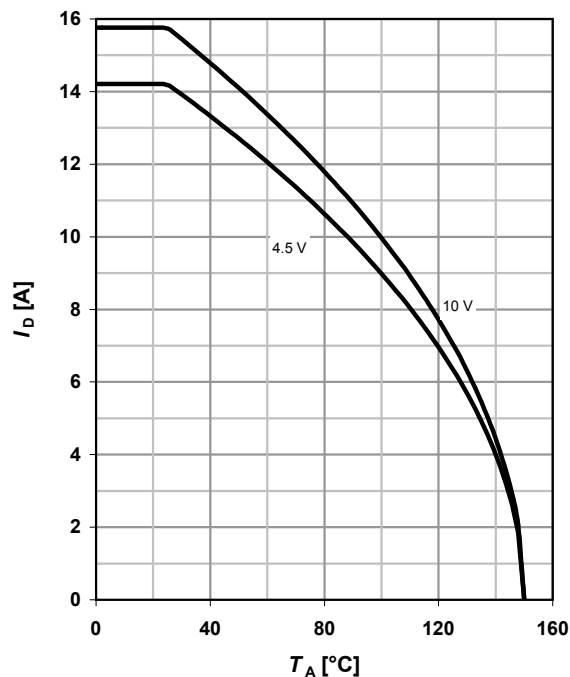
$$P_{\text{tot}} = f(T_A); t_p \leq 10 \text{ s}$$



2 Drain current

$$I_D = f(T_A); t_p \leq 10 \text{ s}$$

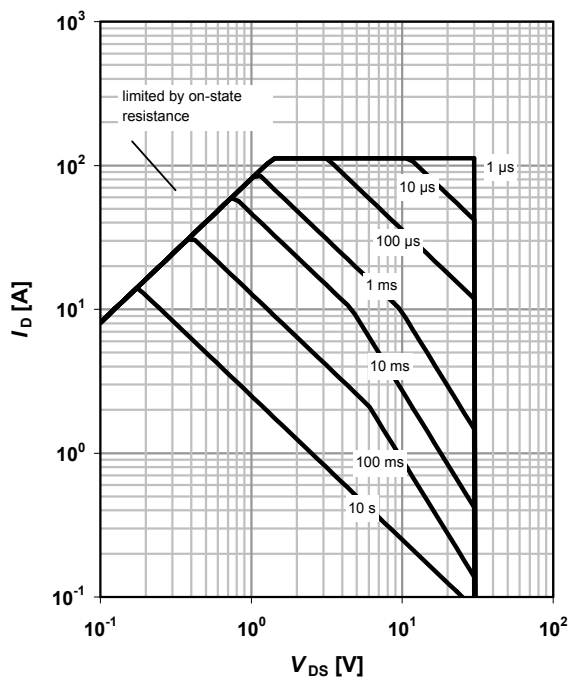
parameter: V_{GS}



3 Safe operating area

$$I_D = f(V_{DS}); T_A = 25^\circ\text{C}^2; D = 0$$

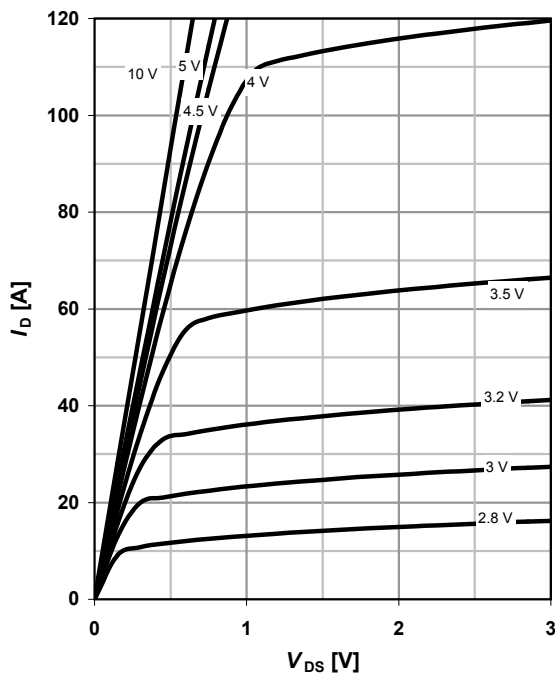
parameter: t_p



5 Typ. output characteristics

$$I_D = f(V_{DS}); T_j = 25^\circ\text{C}$$

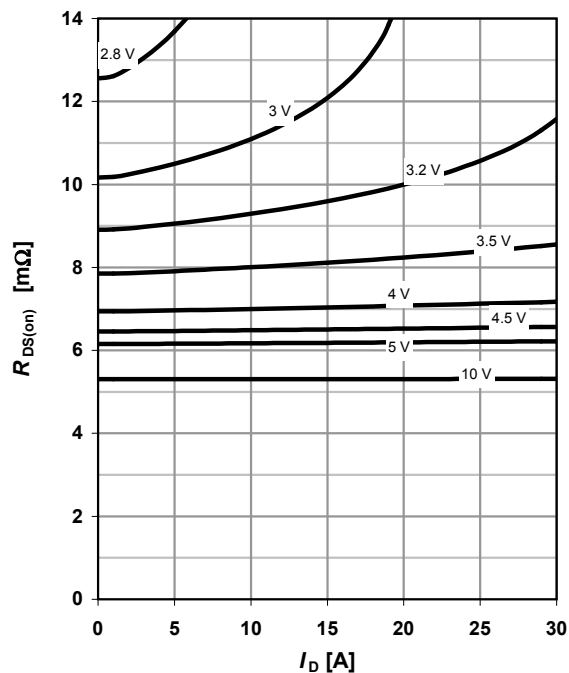
parameter: V_{GS}



6 Typ. drain-source on resistance

$$R_{DS(on)} = f(I_D); T_j = 25^\circ\text{C}$$

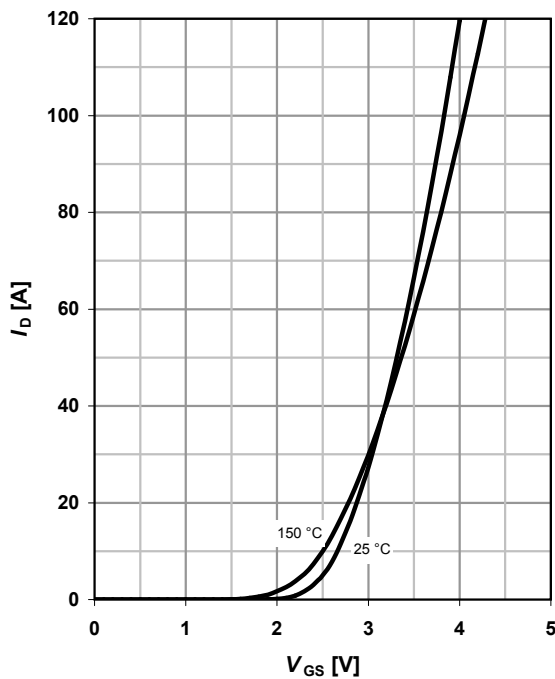
parameter: V_{GS}



7 Typ. transfer characteristics

$$I_D = f(V_{GS}); |V_{DS}| > 2|I_D|R_{DS(on)max}$$

parameter: T_j

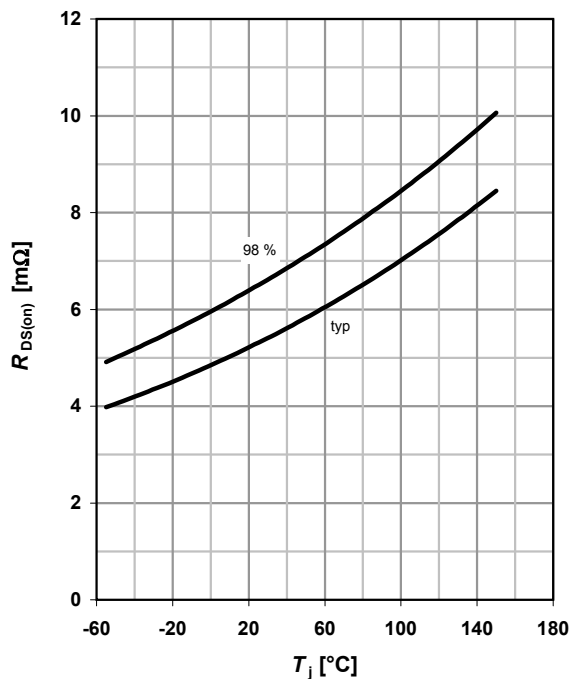


8 Typ. forward transconductance

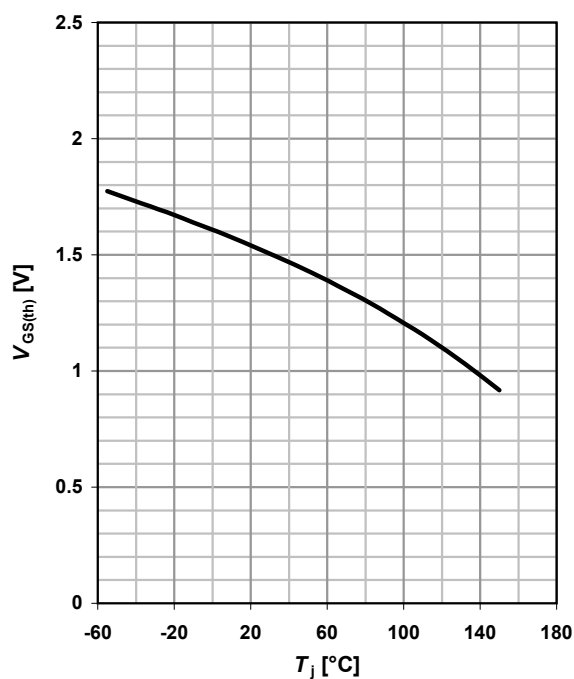
$$g_{fs} = f(I_D); T_j = 25^\circ\text{C}$$

9 Drain-source on-state resistance

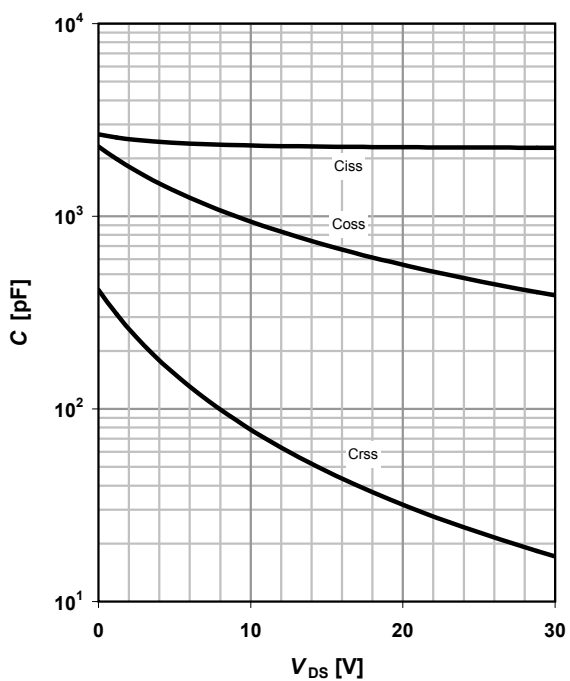
$$R_{DS(on)} = f(T_j); I_D = 16 \text{ A}; V_{GS} = 10 \text{ V}$$


10 Typ. gate threshold voltage

$$V_{GS(th)} = f(T_j); V_{GS} = V_{DS}; I_D = 250 \text{ } \mu\text{A}$$


11 Typ. capacitances

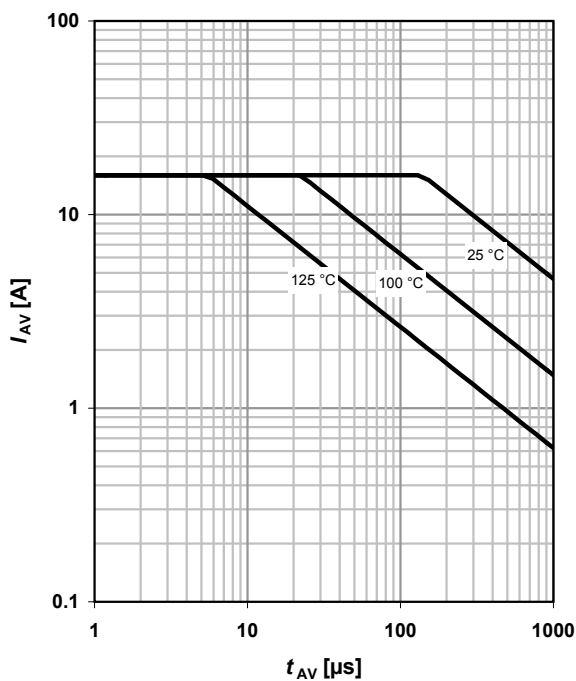
$$C = f(V_{DS}); V_{GS} = 0 \text{ V}; f = 1 \text{ MHz}$$



13 Avalanche characteristics

$$I_{AS}=f(t_{AV}); R_{GS}=25\ \Omega$$

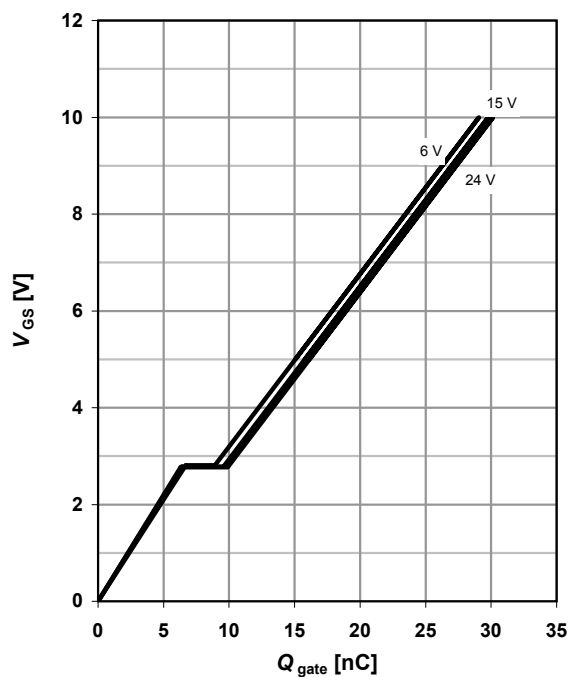
parameter: $T_{j(\text{start})}$



14 Typ. gate charge

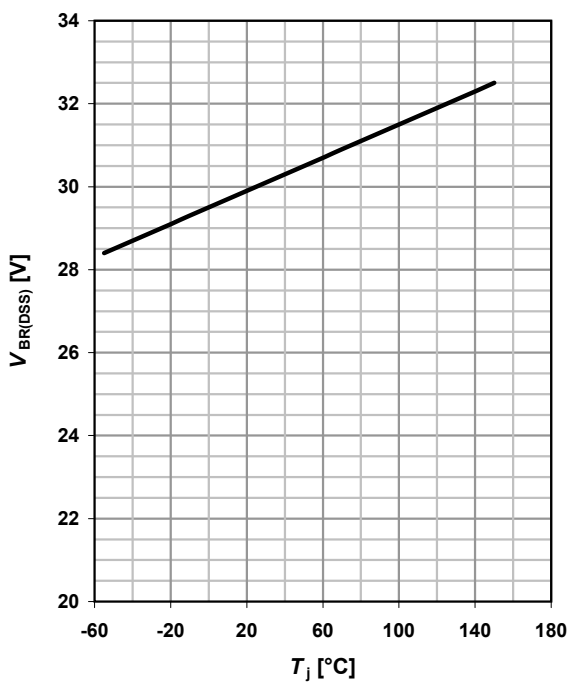
$$V_{GS}=f(Q_{\text{gate}}); I_D=16\ \text{A pulsed}$$

parameter: V_{DD}

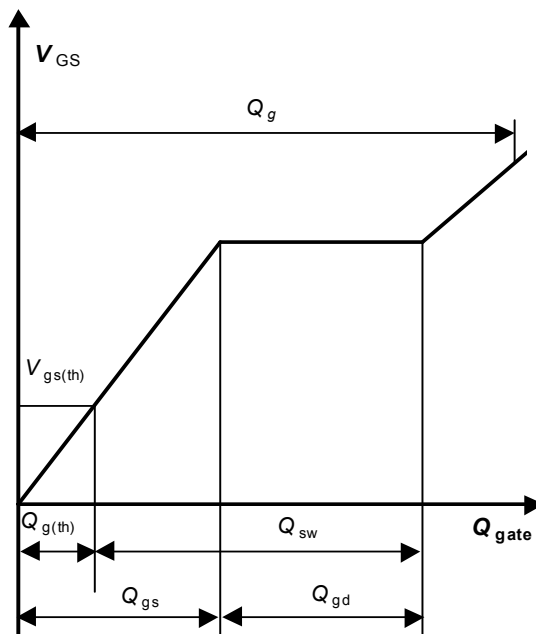


15 Drain-source breakdown voltage

$$V_{BR(DSS)}=f(T_j); I_D=1\ \text{mA}$$

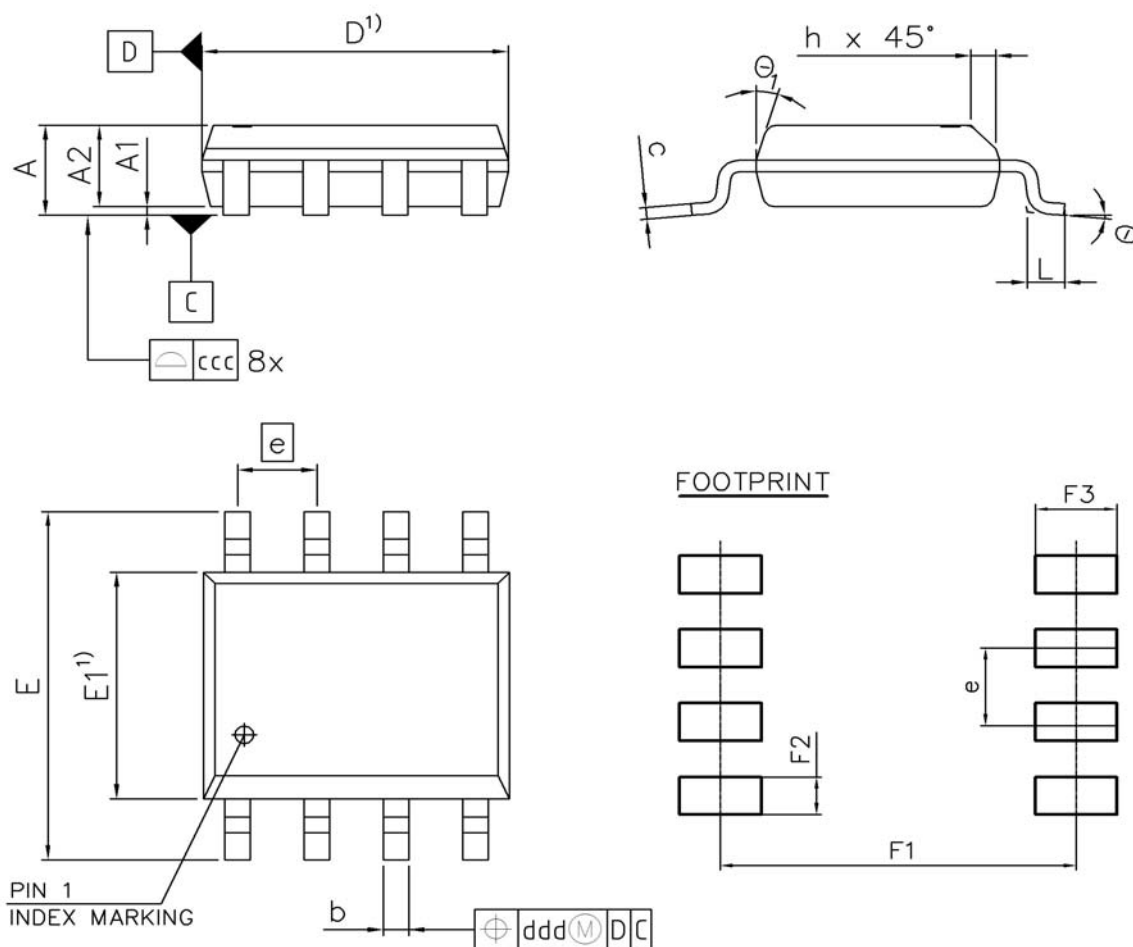


16 Gate charge waveforms



Package Outline

PG-DSO-8: Outline



1) DOES NOT INCLUDE MOLD FLASH OR PROTRUSIONS.

DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	-	1.75	-	0.069
A1	0.10	-	0.004	-
A2	1.25	1.65	0.049	0.065
b	0.35	0.51	0.014	0.020
c	0.17	0.25	0.007	0.010
D	4.80	5.00	0.189	0.197
E	5.80	6.20	0.228	0.244
E1	3.80	4.00	0.150	0.157
e	1.27		0.050	
N	8		8	
L	0.39	0.89	0.015	0.035
h	0.23	0.50	0.009	0.020
Θ	0°	8°	0°	8°
Θ ₁	-	19°	-	19°
ccc	0.10			

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Infineon Technologies AG
81726 Munich, Germany
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